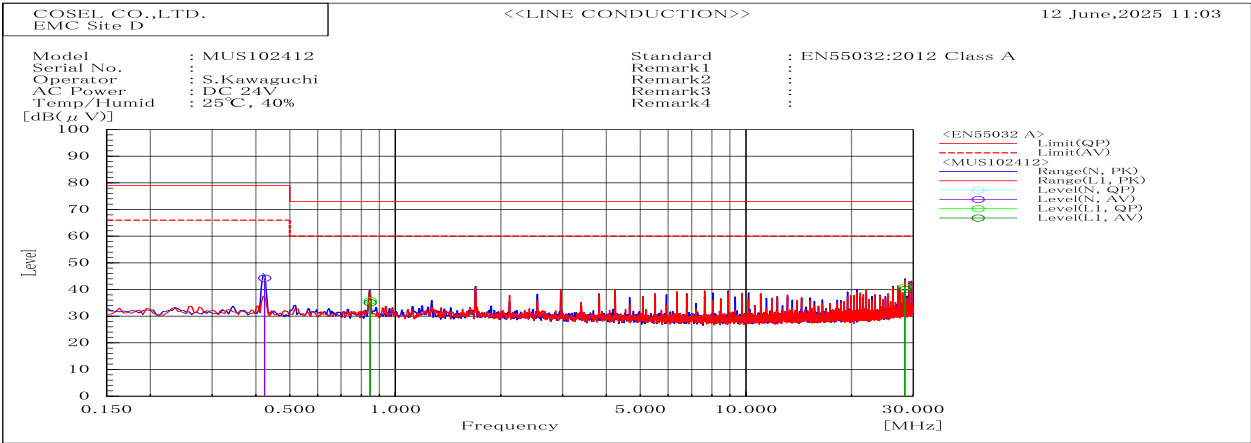
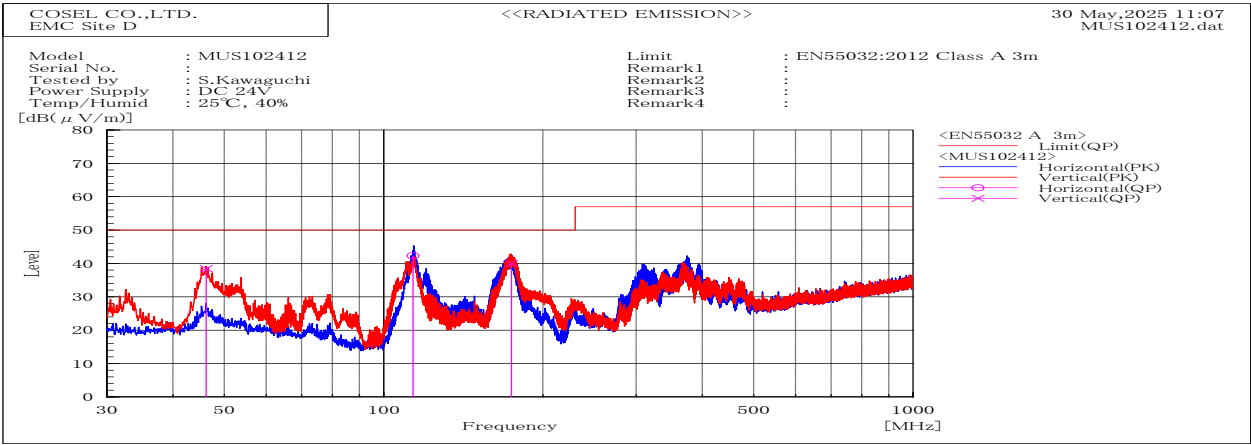


DATA SHEET		Date	12-Jun-25
Model	MUS102412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi



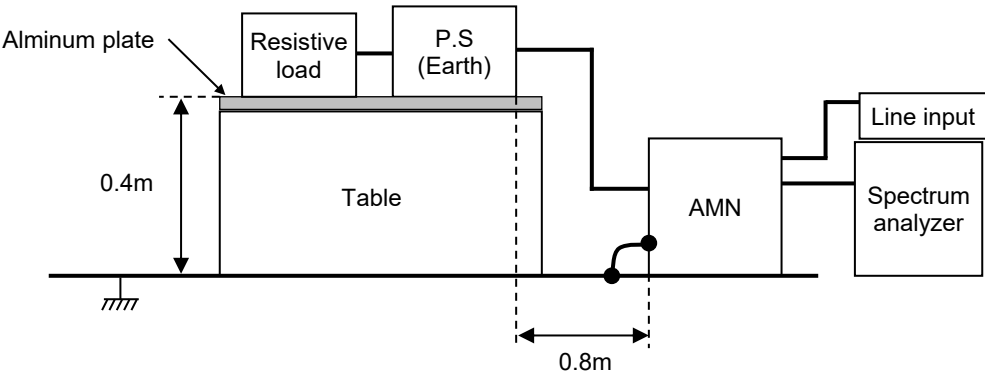
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.847	L1	35.8	35.1	73	60	37.2	24.9	Pass	
28.413	L1	40.9	40	73	60	32.1	20	Pass	
0.424	N	44.5	44.3	79	66	34.5	21.7	Pass	



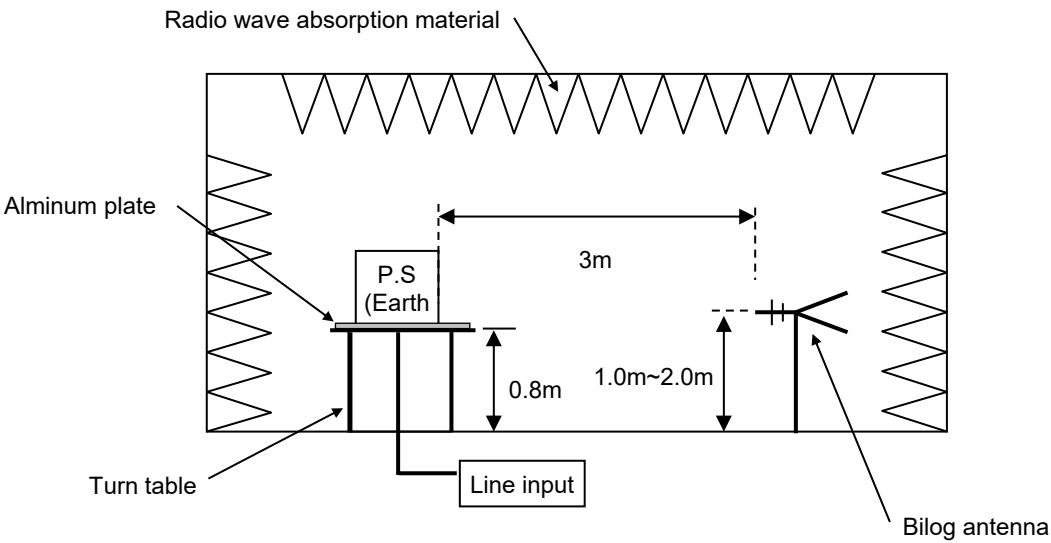
Frequency MHz	Polarization	Stability	Level dB(uV/m)		Limit dB(uV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP		QP				
113.633	H	Stable	42.3	50	7.7	Pass	163.5	266.7		
174.353	V	Stable	40	50	10	Pass	101.5	355.4		
46.231	V	Stable	38.4	50	11.6	Pass	100	350.9		

DATA SHEET		Date	12-Jun-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

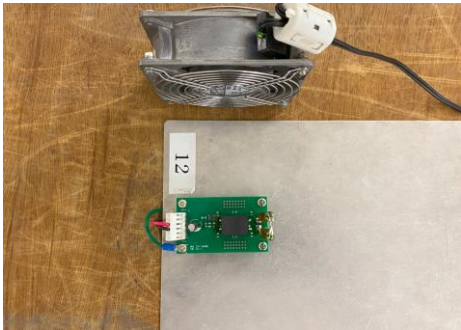
Test : EMI  
 Model Name: MUS10□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

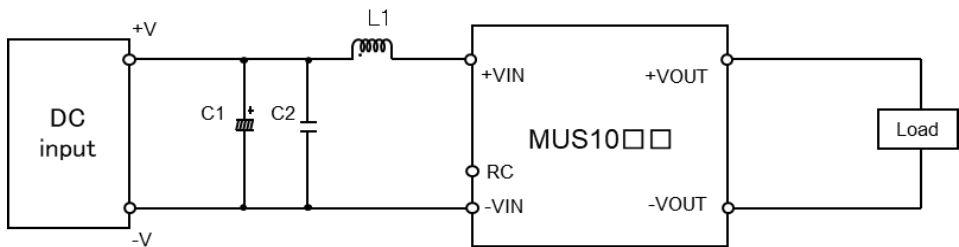


Fig.1 MUS10□□ Testing circuitry

C1 :	MUS1005□	25V 1500 $\mu$ F	Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MUS1012□	50V 100 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS1024□	—	—
	MUS1048□	—	—
C2 :	MUS1005□	16V 22 $\mu$ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS1012□	25V 10 $\mu$ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUS1024□	50V 4.7 $\mu$ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS1048□	100V 2.2 $\mu$ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS1005□	5000mA 2.2 $\mu$ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUS1012□	3500mA 4.7 $\mu$ H	Inductor(LQH5BPN4R7N38 MURATA MANUFACTURING)
	MUS1024□	1600mA 22 $\mu$ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)
	MUS1048□	1100mA 47 $\mu$ H	Inductor(LQH5BPN470M38 MURATA MANUFACTURING)